



INDUSTRY NEWS

New and Interesting at PITTCON-2003

JEOL U.S.A., Inc.

A new, optional structural/chemical analyzer extends the range of SEM analysis. Microscopists can determine chemical, electronic, and atomic structures using JEOL's suite of high resolution SEMs – the JSM-6460/LV, JSM-6360/LV, JSM-6500F, JSM-7400F, and the JAMP-7830F Auger Microprobe – in combination with the new **Renishaw SEM Raman**. The Raman spectrometer provides an unprecedented level of detail, allowing the SEM user to accurately identify polymer materials, crystal quality, crystal orientation, and stress/strain state. For example, a JEOL SEM outfitted with the SEM-Raman can accurately identify a carbon sample as polystyrene or PMMA. Users can take full advantage of the high spatial resolution afforded by the SEM and the chemical information revealed by the Raman, which is sensitive to light element chemistry. SEM-Raman has the unique ability to analyze samples through transparent layers, and provides volume fraction and distribution data. It identifies components by morphology and molecular composition. Applications include polymer and materials science, sub-micron semiconductor particle contamination identification, forensic science, and pharmaceuticals. Telephone: 978-535-5900, Web Address: www.jeol.com

Labstuff "SCIENCE OUTSIDE THE BOX"

Labstuff is an e-commerce site where scientists, researchers, educators, safety and industrial professionals or hobbyists can get high quality lab equipment and supplies at very low prices. Inventory is made up of brand name demo, overstocked, gently used, discontinued merchandise from leading trusted suppliers. Though the majority of our products are of this type, we can also supply you with discounted brand new items. The main headquarters is a 150,000 sq. ft. warehouse near Research Triangle Park, NC with a showroom that can be viewed live on the website. Telephone: 919-567-3833 Web address: www.labstuffonline.com

Industry News and Press Releases

NEW NIKON DXM1200F COLOR DIGITAL CAMERA OFFERS INCREASED SENSITIVITY AND QUANTUM EFFICIENCY

Nikon Instruments Inc. announced the U.S. availability of its new Digital Eclipse DXM1200F high-resolution color digital camera. The camera produces true-to-life, extremely high-quality images with an output capability of up to 12 million pixels and is specifically designed to accommodate fluorescence lighting techniques. The DXM1200F camera's new CCD chip produces images at a sensitivity of up to 2.5 times higher than its predecessor. The result is enhanced and faster image capture in low-illumination applications such as fluorescence, DIC, and dark-field observations. Contact: Victoria Amari, 973-376-9300 vamari@keatingpr.com

Pacific Nanotechnology Announces Improved Nano-R AFM System

Pacific Nanotechnology, Inc. (PNI) announced it has shipped an enhanced Nano-R(TM) AFM system for R&D and industrial lab environments. The Nano-R is the only AFM that offers high-performance, ease of use, and affordability. The improved Nano-R will provide even more applications in areas such as metallurgy, nanoparticles and powders, filters, semiconductor and data storage, photonics, and adhesives.

Higher performance is achieved through both hardware and software enhancements to the tool. The new sample holder has an improved design to accommodate many sample sizes and thicknesses for scanning. The enhanced Nano-R AFM offers an advanced probe exchange mechanism that facilitates the process of exchanging the tip. The tool also features

a new applications programmer interface (API) to National Instruments' LabVIEW(TM), the industry standard data acquisition and instrument control software for customization capabilities. Contact info@pacificnanotechnology.com

FEI Launches VectraVision (TM) System for Advanced Circuit Edit At the 90nm Node

FEI Company introduced its new VectraVision(TM) advanced focused ion beam (FIB) system for circuit edit applications for the 90nm process node. The VectraVision is a critical tool for chip manufacturers facing short development cycles, allowing them to rapidly modify circuit functionality and verifying new circuit designs. The VectraVision incorporates FEI's VisION(TM) ion column -- specifically developed for technologies used in today's microprocessors, digital signal processors, and graphics and wireless chips. More information can be found on the FEI website at: <http://www.feicompany.com>.

EDAX LAUNCHES OIM 2000, 4000 and 7000 SYSTEMS For Electron BackScatter

EDAX Inc., introduces the next generation of Electron Backscatter Diffraction (EBSD) Systems - the OIM 2000, OIM 4000 and OIM 7000 that are designed to meet the needs of a wide range of EBSD users. This release coincides with the release of ChI-Scan - an application that takes advantage of simultaneously collected EDS and EBSD data to more accurately handle multi-phase samples. For further information about EDAX, contact us at: EDAX Inc. Tel: (201) 529-4880, edax.info-international@ametec.com

WITec has introduced the new Mercury 100 AFM System for Materials Research and Nanotechnology

WITec GmbH, Germany has introduced the Mercury 100 AFM, a completely new Atomic Force Microscopy (AFM) system, designed specifically for materials research and nanotechnology. The integrated scientific-grade research microscope and the Digital Pulsed Force Mode, a new measurement mode for AFM, allows nondestructive imaging of various material properties along with the topography. State of the art, highly precise components for scanning, beam deflection or vibration isolation are used to ensure ease of operation and optimized sample investigation. A modular design for the first time guarantees upgrade possibilities from AFM to Confocal / Raman microscopy as well as Scanning Near-field Optical Microscopy (SNOM). Contact: Harald Fischer, Harald.Fischer@WITec.de, www.WITec.de

Digilab announces distribution agreement with Hitachi High Technologies

Digilab, LLC and Hitachi High-Technologies (HHT) announced today a Distribution and Sales Agreement through which Digilab will become HHT's exclusive distributor for Hitachi's UV-Visible/NIR and Fluorescence Molecular Spectroscopy products in North America and Europe. The agreement covers Hitachi's U-1800, U-2810, U-3010, U-3310, and U-4100 models for UV-Visible Spectroscopy applications and the F-2500 and F-4500 models for Fluorescence Spectroscopy solutions. Digilab will also be a non-exclusive distributor for the HHT U-2800 product in Europe.

nPoint Includes SEM Images with Carbon Nanotube AFM Tips

nPoint, Inc., the global leader in ultra-precision motion and control nanopositioners for nanoscale research and manufacturing, introduced a new feature of its ProbeMAX(TM) carbon nanotube (CNT) atomic force microscope (AFM) tips. A scanning electron microscope (SEM) image will be provided of each ProbeMAX tip, allowing the user to select the appropriate probe for their application. CONTACT: Katerina Moloni, +1-608-204-8756, <http://www.piezomax.com>.